





Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 01 P 14516 US (8055-26)	SERIAL NO. 09/931125 Not Yet Assigned
	APPLICANT Randall Rooney et al.	
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
		Schanstra, Ivo, et al., <u>Semiconductor Manufacturing Process Monitoring Using Built-In Self-Test for Embedded Memories</u>	
		Vollrath, Jorg, et al., <u>Compressed Bit Fail Maps for Memory Fail Pattern Classification</u>	
		Vollrath, Joerg, <u>Tutorial: Characterizing SDRAMs</u>	

EXAMINER 	DATE CONSIDERED 1/23/04
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	